

1. Global joint venture starts operations as WeEn Semiconductors

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WeEn Semiconductors



Product data sheet

1. General description

Planar passivated SCR with sensitive gate in a SOT223 surface mountable plastic package. This SCR is designed to be interfaced directly to microcontrollers, logic integrated circuits and other low power gate trigger circuits.

2. Features and benefits

- Sensitive gate
- Planar passivated for voltage ruggedness and reliability
- Direct triggering from low power drivers and logic ICs
- Surface mountable package

3. Applications

- Circuit breakers
- RCD/GFI/LCCB applications

4. Quick reference data

Table 1. Quick reference data

Symbol	Parameter	Conditions		Min	Тур	Max	Unit
V_{DRM}	repetitive peak off- state voltage		[1]	-	-	600	V
V _{RRM}	repetitive peak reverse voltage			-	-	600	V
I _{TSM}	non-repetitive peak on- state current	half sine wave; $T_{j(init)} = 25 \text{ °C}$; $t_p = 10 \text{ ms}$; Fig. 4; Fig. 5		-	-	8	A
I _{T(AV)}	average on-state current	half sine wave; T _{sp} ≤ 112 °C; <u>Fig. 1</u>		-	-	0.63	Α
I _{T(RMS)}	RMS on-state current	half sine wave; $T_{sp} \le 112 ^{\circ}\text{C}$; Fig. 3		-	-	1	A
Static characteristics							
I _{GT}	gate trigger current	$V_D = 12 \text{ V}; I_T = 10 \text{ mA}; T_j = 25 ^{\circ}\text{C};$ Fig. 9		20	50	200	μΑ

^[1] Although not recommended, off-state voltages up to 800 V may be applied without damage, but the thyristor may switch to the on-state.





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5. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	K	cathode	4	A
2	Α	anode		G sym037
3	G	gate		3
4	mb	mb; connected to anode	☐1 ☐2 ☐3 SC-73 (SOT223)	

6. Ordering information

Table 3. Ordering information

Type number	Package	е					
	Name	Description	Version				
BT168GW	SC-73	plastic surface-mounted package with increased heatsink; 4 leads	SOT223				

SCR

7. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions		Min	Max	Unit
V_{DRM}	repetitive peak off-state voltage		[1]	-	600	V
V_{RRM}	repetitive peak reverse voltage			-	600	V
I _{T(AV)}	average on-state current	half sine wave; T _{sp} ≤ 112 °C; <u>Fig. 1</u>		-	0.63	Α
I _{T(RMS)}	RMS on-state current	half sine wave; $T_{sp} \le 112 ^{\circ}\text{C}$; Fig. 2; Fig. 3		-	1	А
I _{TSM}	non-repetitive peak on-state current	half sine wave; $T_{j(init)} = 25 \text{ °C}$; $t_p = 10 \text{ ms}$; Fig. 4; Fig. 5		-	8	A
		half sine wave; $T_{j(init)} = 25 \text{ °C}$; $t_p = 8.3 \text{ ms}$		-	9	A
I ² t	I ² t for fusing	t _p = 10 ms; SIN		-	0.32	A ² s
dl _T /dt	rate of rise of on-state current	$I_T = 2 \text{ A}$; $I_G = 10 \text{ mA}$; $dI_G/dt = 100 \text{ mA}/\mu s$		-	50	A/µs
I _{GM}	peak gate current			-	1	Α
V_{RGM}	peak reverse gate voltage			-	5	V
P_GM	peak gate power			-	2	W
P _{G(AV)}	average gate power	over any 20 ms period		-	0.1	W
T _{stg}	storage temperature			-40	150	°C
Tj	junction temperature			-	125	°C

^[1] Although not recommended, off-state voltages up to 800 V may be applied without damage, but the thyristor may switch to the on-state.

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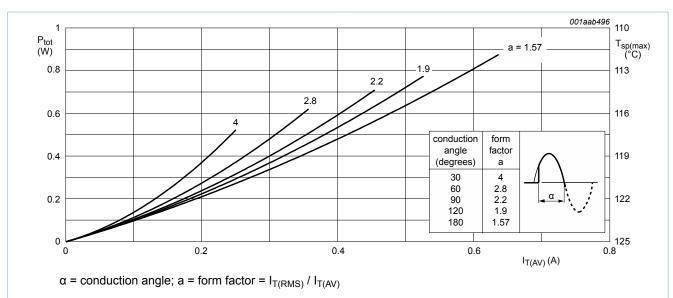


Fig. 1. Total power dissipation as a function of average on-state current; maximum values

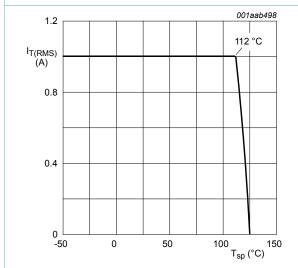
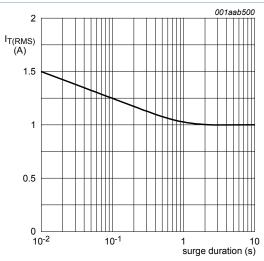


Fig. 2. RMS on-state current as a function of solder point temperature; maximum values



 $f = 50 \text{ Hz}; T_{sp} = 112 ^{\circ}\text{C}$

Fig. 3. RMS on-state current as a function of surge duration; maximum values

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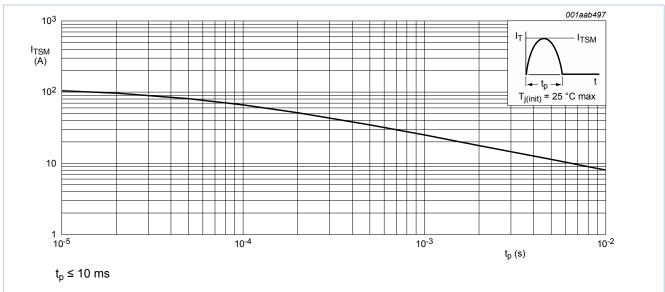


Fig. 4. Non-repetitive peak on-state current as a function of pulse width for sinusoidal currents; maximum values

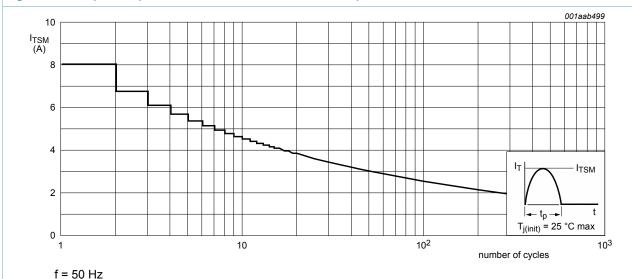


Fig. 5. Non-repetitive peak on-state current as a function of the number of sinusoidal current cycles; maximum values

SCR

8. Thermal characteristics

Table 5. Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
R _{th(j-sp)}	thermal resistance from junction to solder point	Fig. 6	-	-	15	K/W
R _{th(j-a)}	thermal resistance from junction to	printed circuit board mounted; minimum footprint; Fig. 7	-	156	-	K/W
	ambient	printed circuit board mounted; pad area; Fig. 8	-	70	-	K/W

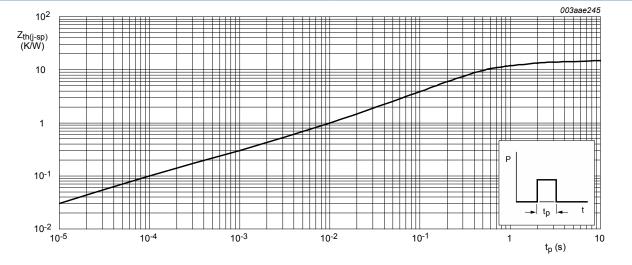
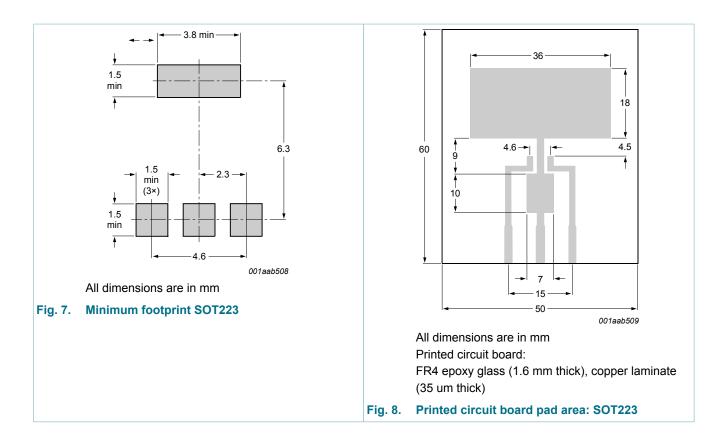


Fig. 6. Transient thermal impedance from junction to solder point as a function of pulse width

SCR



7 / 15

SCR

9. Characteristics

Table 6. Characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static char	acteristics					
I _{GT}	gate trigger current	$V_D = 12 \text{ V}; I_T = 10 \text{ mA}; T_j = 25 \text{ °C};$ Fig. 9	20	50	200	μA
l _L	latching current	V_D = 12 V; I_G = 0.5 mA; R_{GK} = 1 k Ω ; T_j = 25 °C; <u>Fig. 10</u>	-	2	6	mA
l _H	holding current	$V_D = 12 \text{ V}; R_{GK} = 1 \text{ k}\Omega; T_j = 25 \text{ °C};$ Fig. 11	-	2	5	mA
V _T	on-state voltage	I _T = 1.2 A; T _j = 25 °C; <u>Fig. 12</u>	-	1.25	1.7	V
V _{GT}	gate trigger voltage	$V_D = 12 \text{ V}; I_T = 10 \text{ mA}; T_j = 25 ^{\circ}\text{C};$ Fig. 13	-	0.5	0.8	V
		V_D = 600 V; I_T = 10 mA; T_j = 125 °C	0.2	0.3	-	V
I _D	off-state current	$V_D = 600 \text{ V}; T_j = 125 \text{ °C}; R_{GK} = 1 \text{ k}\Omega$	-	0.05	0.1	mA
I _R	reverse current	$V_R = 600 \text{ V}; T_j = 125 \text{ °C}; R_{GK} = 1 \text{ k}\Omega$	-	0.05	0.1	mA
Dynamic c	haracteristics	1				
_	rate of rise of off-state voltage	V_{DM} = 402 V; T_j = 125 °C; R_{GK} = 1 kΩ; $(V_{DM}$ = 67% of V_{DRM}); exponential waveform; Fig. 14	500	800	-	V/µs
		V_{DM} = 402 V; T_j = 125 °C; (V_{DM} = 67% of V_{DRM}); exponential waveform; gate open circuit; <u>Fig. 14</u>	-	25	-	V/µs
t _{gt}	gate-controlled turn-on time	I_{TM} = 2 A; V_D = 600 V; I_G = 10 mA; $dI_G/$ dt = 0.1 A/µs; T_j = 25 °C	-	2	-	μs
t _q	commutated turn-off time	$\begin{split} &V_{DM} = 402 \text{ V}; \text{ T}_{j} = 125 \text{ °C}; \text{ I}_{TM} = 1.6 \text{ A}; \\ &V_{R} = 35 \text{ V}; (\text{dI}_{T}/\text{dt})_{M} = 30 \text{ A}/\mu\text{s}; \text{ dV}_{D}/\\ &\text{dt} = 2 \text{ V}/\mu\text{s}; \text{ R}_{GK} = 1 \text{ k}\Omega; (\text{V}_{DM} = 67\% \text{ of } \text{V}_{DRM}) \end{split}$	-	100	-	μs

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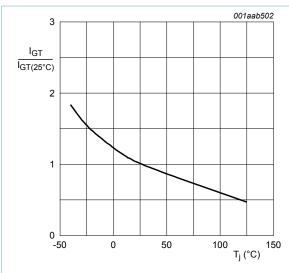


Fig. 9. Normalized gate trigger current as a function of junction temperature

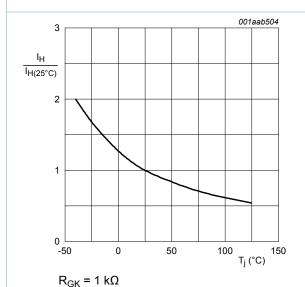
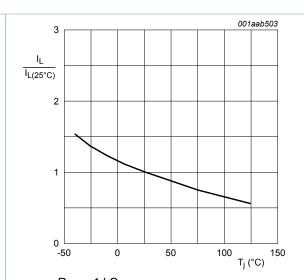
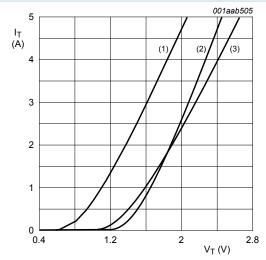


Fig. 11. Normalized holding current as a function of junction temperature



 $R_{GK} = 1 k\Omega$

Fig. 10. Normalized latching current as a function of junction temperature



 $V_0 = 1.0 \text{ V}; R_s = 0.27 \Omega$

(1) T_i = 125 °C; typical values

(2) T_i = 125 °C; maximum values

(3) T_i = 25 °C; maximum values

Fig. 12. On-state current as a function of on-state voltage

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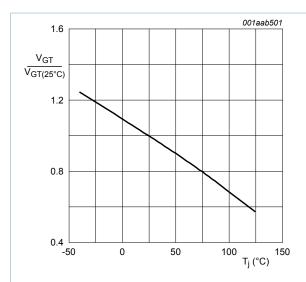


Fig. 13. Normalized gate trigger voltage as a function of junction temperature

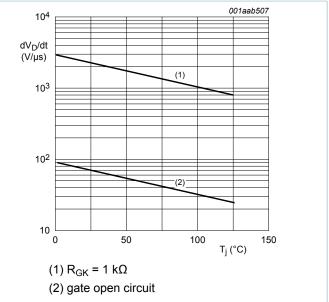
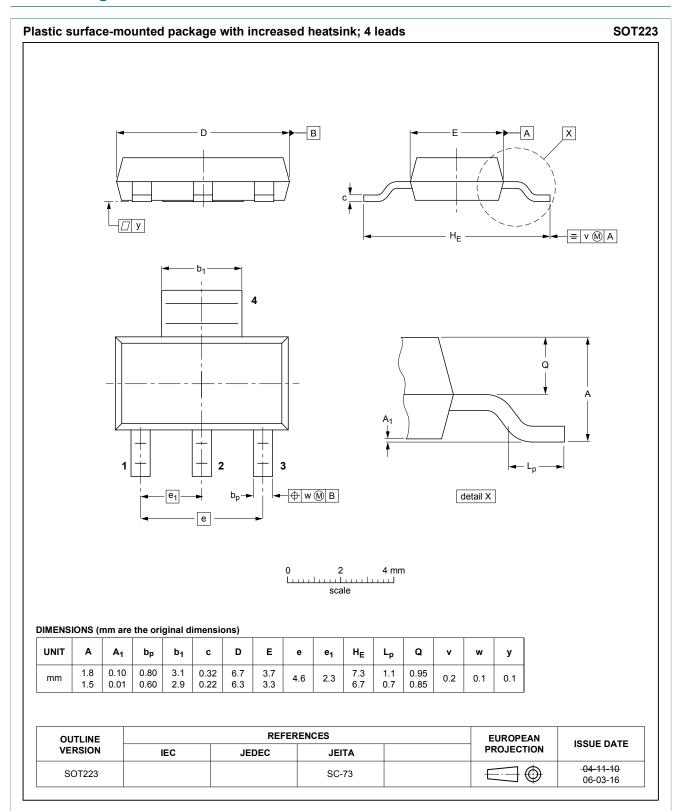


Fig. 14. Critical rate of rise of off-state voltage as a function of junction temperature; typical values

10 / 15

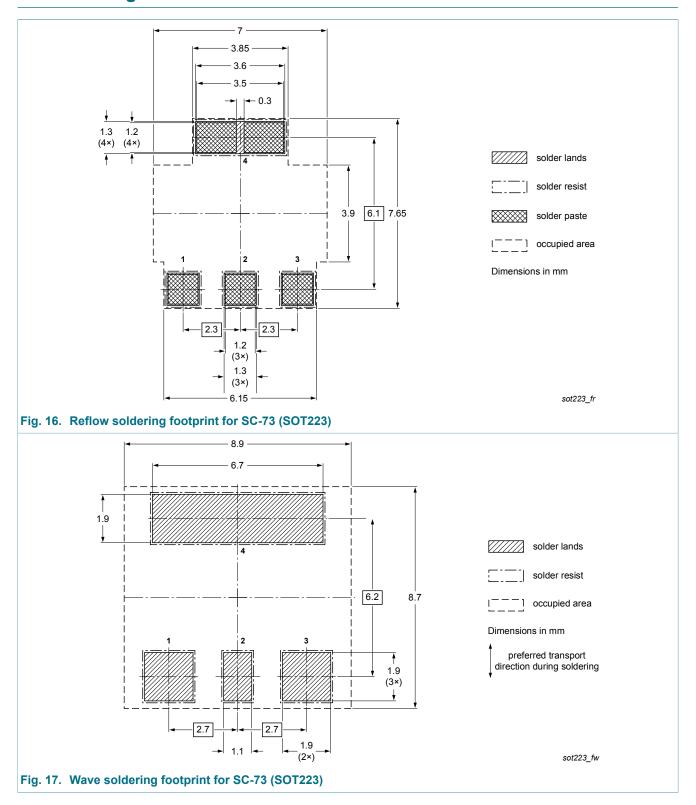
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10. Package outline



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11. Soldering



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12. Legal information

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Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
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13. Contents

1	General description	1
2	Features and benefits	1
3	Applications	1
4	Quick reference data	1
5	Pinning information	2
6	Ordering information	2
7	Limiting values	3
8	Thermal characteristics	6
9	Characteristics	8
10	Package outline	11
11	Soldering	12
12	Legal information	13
12.1	Data sheet status	13
12.2	Definitions	13
12.3	Disclaimers	13
12.4	Trademarks	14

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